

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	((FET or ((field adj effect) adj transistor)) same coordinates) and (signal adj integrity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:52
L2	8	((FET or ((field adj effect) adj transistor)) same (coordinate\$2 or location\$2)) and (signal adj integrity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:54
L3	0	((FET or ((field adj effect) adj transistor)) same (coordinate\$2 or location\$2)) same (signal adj integrity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:54
L4	0	((FET or ((field adj effect) adj transistor)) same (coordinate\$2 or location\$2)) and (signal adj integrity) and (well adj edge)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:54
S1	2592	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 11:24
S2	2000	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 11:17
S3	2101	716/1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 11:17
S4	0	(716/4).ccls. and (identify\$4 or determin\$4) same (FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 11:28
S5	1	(716/5).ccls. and (identify\$4 or determin\$4) same (FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 11:28

EAST Search History

S6	0	(716/1).ccls. and (identify\$4 or determin\$4) same (FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 11:29
S7	1	("716"/\$).ccls. and (identify\$4 or determin\$4) same (FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 11:29
S8	2	(identify\$4 or determin\$4) same (FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:20
S9	2	(identify\$4 or determin\$4) and (FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:21
S10	1	((identify\$4 or determin\$4) and (FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:21
S11	2	(FET or ((field adj effect) adj transistor)) and ((signal adj integrity) adj failure)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:22
S12	384	(FET or ((field adj effect) adj transistor)) and (signal adj integrity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:22
S13	13	(FET or ((field adj effect) adj transistor)) same (signal adj integrity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:24
S14	2	(FET or ((field adj effect) adj transistor)) same (signal adj integrity) same fail\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:23
S15	2	((FET or ((field adj effect) adj transistor)) same (signal adj integrity)) and ((threshold adj distance) same (well adj edge))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:26

EAST Search History

S16	2	((FET or ((field adj effect) adj transistor)) same (signal adj integrity)) and ((threshold adj distance) and (well adj edge))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:50
S17	2	((FET or ((field adj effect) adj transistor)) and (signal adj integrity)) and ((threshold adj distance) and (well adj edge))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:26
S18	1	((FET or ((field adj effect) adj transistor)) and (signal adj integrity)) and ((threshold adj distance) and (well adj edge))). CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/04/28 12:26

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

[Search Results](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(((fet) <and> (signal integrity failure))<in>metadata)"

[e-mail](#)Your search matched **0** documents.A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» Search Options

[View Session History](#)[New Search](#)

Modify Search

(((fet) <and> (signal integrity failure))<in>metadata)

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

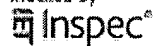
IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

No results were found.

Please edit your search criteria and try again. Refer to the Help pages if you need assistance with your search.

Indexed by

[Help](#) [Contact Us](#) [Privacy & Policy](#)

© Copyright 2006 IEEE – All Rights Reserved

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

[Search Results](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(((field effect transistor) <and> (signal integrity) <and> (fail))<in>metadata)"

e-mail

Your search matched **0** documents.A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» Search Options

[View Session History](#)[New Search](#)

Modify Search

Search☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

No results were found.

Please edit your search criteria and try again. Refer to the Help pages if you need assistance.

Indexed by

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2006 IEEE -

[Sign in](#)[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#) [Maps](#) [more »](#)

(FET)("well edge") "signal integrity failure"

[Advanced Search](#)
[Preferences](#)**Web**


Results 1 - 2 of 2 for (FET)("well edge") "signal integrity failure". (0.44 seconds)

Tip: Try removing quotes from your search to get more results.

Integrated circuit design for signal integrity, avoiding well ...When one of these tools indicates a **signal integrity failure**, a designer must ... of signal integrity caused by a closeness of a **FET** edge to a **well edge**. ...www.freshpatents.com/ Integrated-circuit-design-for-signal-integrity-avoiding-well-proximity-effects-dt200... - 30k - [Cached](#) - [Similar pages](#)**美国专利申请公开说明书20050210431 - INTEGRATED CIRCUIT DESIGN FOR ...** - [[Translate this page](#)]... any field effect transistor (**FET**) that causes a **signal integrity failure** in ... a failing **FET** that is closer than a threshold distance to a **well edge**. ...cxp.pattera.com/uspregrant20050210431cn.html - 27k - [Cached](#) - [Similar pages](#)New! Crack the Code: [Play the Da Vinci Code Quest on Google](#). [Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2006 Google

[Sign in](#)


[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#) [Maps](#) [more »](#)

[Advanced Search](#)
[Preferences](#)

Web

Results 1 - 8 of about 10 for (FET)("well edge")(fail) "signal integrity". (1.23 seconds)

Integrated circuit design for **signal integrity**, avoiding well ...

... of **signal integrity** caused by a closeness of a **FET** edge to a **well edge**. ... If the IC design **fails** the integrity analysis again (NO at step S5), ...

www.freshpatents.com/ Integrated-circuit-design-for-signal-integrity-avoiding-well-proximity-effects-dt200... - 30k - [Cached](#) - [Similar pages](#)

[PDF] MN Fourth Quarter

File Format: PDF/Adobe Acrobat - [View as HTML](#)

part of The redundant Switch **fails**. In normal operation, when Two Switch fabrics ... Printed-circuit-Board insulator material), **signal integrity** is A ...

www.ibm.com/chips/micronews/ vol6_no4/MN_vol6_no4_fnl.pdf - Supplemental Result - [Similar pages](#)

美国专利申请公开说明书20050210431 - INTEGRATED CIRCUIT DESIGN FOR ... - [[Translate this page](#)]

INTEGRATED CIRCUIT DESIGN FOR **SIGNAL INTEGRITY**, AVOIDING WELL PROXIMITY EFFECTS ... a failing **FET** that is closer than a threshold distance to a **well edge**. ...

cxp.pattera.com/uspregrant20050210431cn.html - 27k - [Cached](#) - [Similar pages](#)

LECC 2001 WORKSHOP

The consequence is: if an ELMB would **fail**, only one longitudinal segment is affectedd.. ...

Title: PRINTED CIRCUIT BOARD **SIGNAL INTEGRITY** ANALYSIS AT CERN ...

ph-collectif-lecc-workshops.web.cern.ch/ ph-collectif-lecc-workshops/Stockholm/lecc_2001_abstracts.html - 146k - [Cached](#) - [Similar pages](#)

[doc] Sorting Devices for the CSC Muon Trigger System at CMS

File Format: Microsoft Word - [View as HTML](#)

The consequence is: if an ELMB would **fail**, only one longitudinal segment is affectedd.. ...

PRINTED CIRCUIT BOARD **SIGNAL INTEGRITY** ANALYSIS AT CERN ...

ph-collectif-lecc-workshops.web.cern.ch/ ph-collectif-lecc-workshops/Stockholm/Abstract2001.doc - [Similar pages](#)

[PDF] MN Fourth Quarter

File Format: PDF/Adobe Acrobat - [View as HTML](#)

Early detection of **signal-integrity** problems can result in large ... which entailed a modification of the **FET** halos to avoid degra- ...

www-03.ibm.com/chips/micronews/ vol6_no4/MN_vol6_no4_fnl.pdf - [Similar pages](#)

[PDF] CMOS14TB Design Reference Manual HP ICBD Confidential Do Not Duplicate

File Format: PDF/Adobe Acrobat

if the emitter is placed close to the **Well edge**, significant ... In cases where a **FET** is of interest only insofar as the load it presents to the circuit ...

joule.bu.edu/~hazen/DataSheets/MOSIS/A-5960-7152-1.pdf - [Similar pages](#)

lecc2001 all abstracts and summaries

the consequence is: if An ELMB would **fail**, only one longitudinal segment is affectedd.. the low Voltage regulators have a current limitation. ...

nicewww.cern.ch/lebwshop/Stockholm/lec2001abstsum.html - 340k - Supplemental Result -